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D Goder, WR Pelletier - Proc. HFPC, 1996

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V Stopiaková, H Manhaeve, M ... - ... , automation and test in ..., 1999 - portal acm.org

... due to the fact that these failures may prevent changes of the quiescent power supply current

[5]-[6]. Therefore, the transient power supply current testing (I DDT testing) [7]-[8] can be

conveniently used to augment the existing \emph{test} methods and to enhance the defect coverage. ...

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... all attempts of input signal selection, and a compu-tationally expensive transient circuit simulation ...

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GH Weiss, DE Young - Electrical Overstress/Electrostatic Discharge ..., 1995

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DK Su, MJ Loinaz, S Masui, BA Wooley - IEEE Journal of Solid-State Circuits. 1993

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- c) 20 amp current transients at ... An HP4291 is used to measure capacitor ESR by soldering it to an SMA connector and attaching it to a **test** head through an APC-7 connector. ...

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J Liu, RZ Makki, A Kayssi - Journal of Electronic Testing, 2000 - Springer ... use of the dy-namic power supply current, i DDT, for testing SRAMs ... Any time a cell switches

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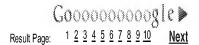
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G Gielen, Z Wang, W Sansen - Proceedings of the 1994 IEEE/ACM ..., 1994 - portal acm.org

... on the parameters of the kth type of faulty circuit, transient simulation and ... B. Bannister, "Can supply cur- rent monitoring be applied to the **testing** of analog as ... [3] D. Papakostas, A. Hatzopoulos,

"Analogue fault identification based on power supply current spectrum," Electronics ...

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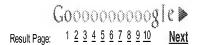
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... Note that the defect-free responses in Figures 4 and 6 are different because a different test pattern was used in each case. ... in the FCMOS circuit also have a similar iDDT (recall that iDDT is directly com- puted from the transient portion of the AVDD waveform) current response. ...

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... This technique uses a Genetic Algorithm-based approach to generate patterns that maximize the ... IC's maximum operating frequency (Fmax) to establish a multi-parameter test technique for ... intrinsic and extrinsic (defect) leakages in IC's with high background stand-by current. ...

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Y Min, Z Li - Journal of Electronic Testing, 1998 - Springer

... where δ shows the variation times of average transient current between the fault-free and faulty circuits ... The IDDT test generation is to find a test vector pair to maximize the value of given by (6) for ... resolution limit, the fault is IDDT testable, and {\v1,\v2} is then the test pattern pair to ...

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... This requires, in part, the use of fault isolation circuitry for each pseudo-partition (see Section

4.2). ... This algorithm in-cludes the following two steps. Step 1. In this step the test vectors are gener- ated. ... Page 9. Transient Power Supply Current Monitoring 31 ...

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... supply current of the IC [21]. ... Many companies perform some form of I,., testing, such as power down tests, with a small set of testpatterns (vectors ... The Z, ., pseudo stuck-at-fault (PSAF) test applies a SAF vector pattern to the input nodes of each logic gate, but only propagates the ...

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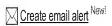
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... Erroneous switching of a cell will result in an unexpected **transient current** level in the **power supply**. ... The i DDT **test** method was shown to detect all disturb **faults**, including read-destruct **faults** using a short **test** length of 5n where n is the number of cells, but this **test** method ...

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Y Min, Z Li - Journal of Electronic Testing, 1998 - Springer

... When some inputs change from logic 1(0) to logic 0(1), the **power supply** current ... where δ shows the variation times of average **transient current** between the **fault**-free and faulty circuits. ... hardware resolution limit, the **fault** is IDDT testable, and $\{v1,v2\}$ is then the **test pattern** pair to ...

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B Kruseman - IEEE European Test Workshop, 2000. Proceedings, 2000

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... is typically on the order of tens of nancamperes, while the **transient current** may reach ... Therefore, the average **power** dissipation overhead is about 12.4% due to the in ... Future work includes automatic **test** equipment interfacing, **test pattern** generation, and partitioning of large ...

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